TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L<sup>2</sup>-π-MOSV)

# 2SK2376

# Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain-source ON resistance  $: RDS (ON) = 13 \text{ m}\Omega \text{ (typ.)}$ 

 $\bullet~$  High forward transfer admittance ~ :  $|\,Y_{fs}\,|$  = 40 S (typ.)

• Low leakage current :  $IDSS = 100 \mu A (max) (VDS = 60 V)$ 

• Enhancement mode  $: V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA)}$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	60	V	
Drain-gate voltage (R	<sub>GS</sub> = 20 kΩ)	$V_{DGR}$	60	V	
Gate-source voltage		$V_{GSS}$	±20	٧	
Drain current	DC (Note 1)	I <sub>D</sub>	45	Α	
	Pulse (Note 1)	$I_{DP}$	180	Α	
Drain power dissipatio	n (Tc = 25°C)	$P_{D}$	100	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	701	mJ	
Avalanche current		I <sub>AR</sub>	45	Α	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	10	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	1.25	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	83.3	°C/W

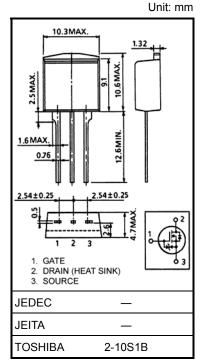
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 25 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial),  $L = 471 \mu\text{H}$ ,  $R_G = 25 \Omega$ ,  $I_{AR} = 45 \text{ A}$ 

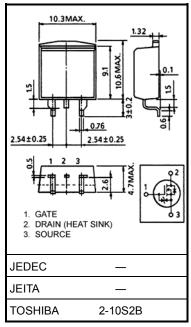
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



Weight: 1.5 g (typ.)



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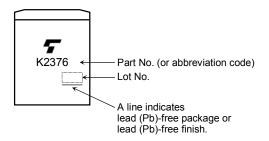
### **Electrical Characteristics (Ta = 25°C)**

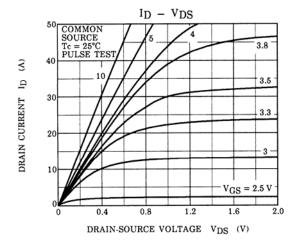
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μA
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_	_	V
Gate threshold v	roltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.8	_	2.0	V
Drain acurae ON register		R <sub>DS (ON)</sub>	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 25 A	_	19	25	mΩ
Drain-source ON resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 25 A		_	13	17		
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 25 A	28	40	_	S
Input capacitano	e	C <sub>iss</sub>		_	3350	_	
Reverse transfer	leverse transfer capacitance $C_{rss}$ $V_{DS}$ = 10 V, $V_{GS}$ = 0 V, f = 1 MHz		_	550	_	pF	
Output capacitance		Coss		_	1600	_	
Switching time –	Rise time	t <sub>r</sub>	$V_{GS} = \frac{10V}{0V}$ $V_{GS} = \frac{10V}{0V}$ $V_{OUT}$ $R_{L} = \frac{1.2\Omega}{1.2\Omega}$ $V_{DD} = 30V$ $Duty \leq 1\%, t_{W} = 10\mu s$	_	25	_	
	Turn-on time	t <sub>on</sub>		_	55	_	- ns
	Fall time	t <sub>f</sub>		_	60	_	
	Turn-off time	t <sub>off</sub>		_	180	_	
Total gate charg plus gate-drain)		Qg			110		
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ 48 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 45 A		70		nC
Gate-drain ("miller") charge		$Q_{gd}$			40	1	

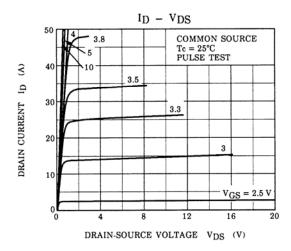
### Source-Drain Ratings and Characteristics (Ta = 25°C)

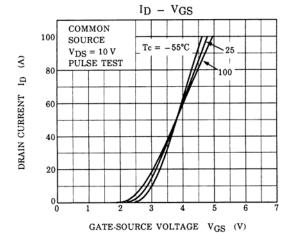
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	1	_	45	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_		_	180	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V		_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V	_	120	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> / dt = 50 A / μs	-	0.2	_	μC

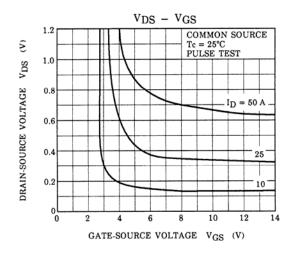
## Marking

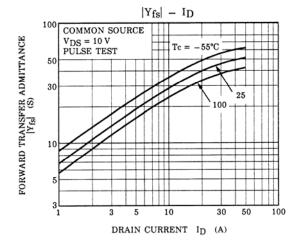


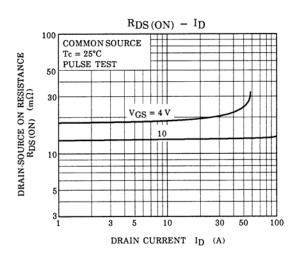


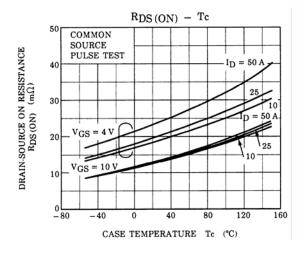


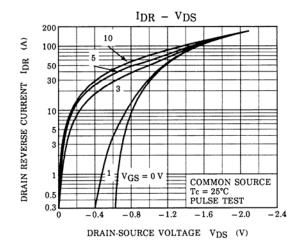


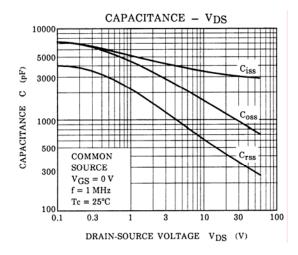


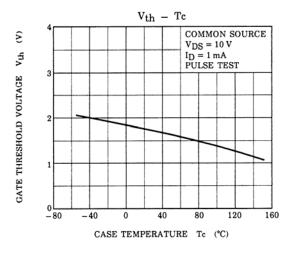


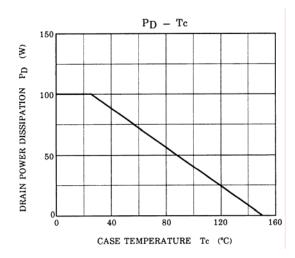


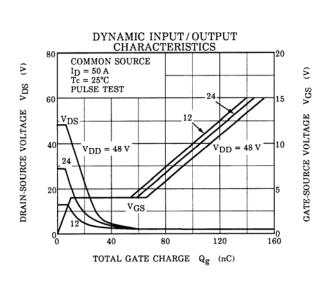




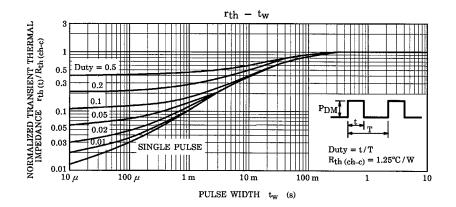


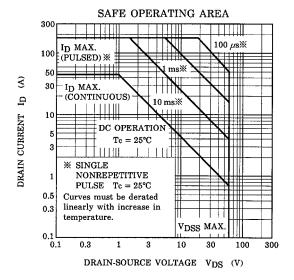


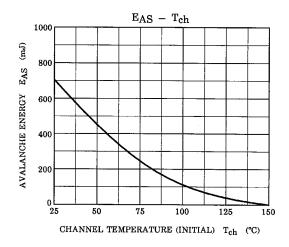


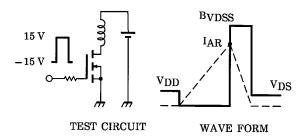


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$$\begin{aligned} &RG = 25 \ \Omega \\ &V_{DD} = 25 \ \text{V}, \ L = 471 \ \mu\text{H} \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right)$$

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